



# STD17NF03L

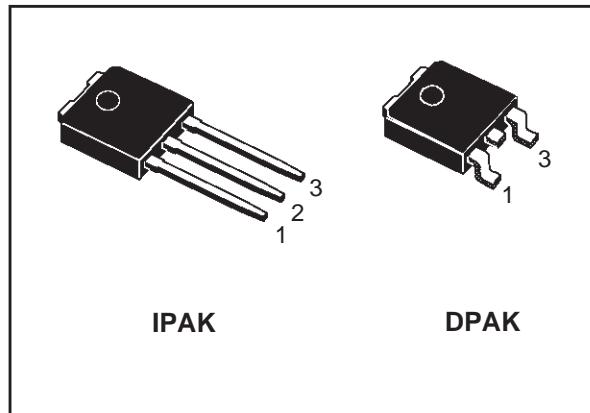
## N-CHANNEL 30V - 0.038Ω - 17A - DPAK/IPAK STripFET™ POWER MOSFET

TYPE	V <sub>DSS</sub>	R <sub>D(on)</sub>	I <sub>D</sub>
STD17NF03L	30V	<0.05Ω	17A

- TYPICAL R<sub>D(on)</sub> = 0.038Ω
- EXCEPTIONAL dv/dt CAPABILITY
- APPLICATION ORIENTED CHARACTERIZATION
- ADD SUFFIX "T4" FOR ORDERING IN TAPE & REEL
- ADD SUFFIX "-1" FOR ORDERING IN IPAK VERSION

### DESCRIPTION

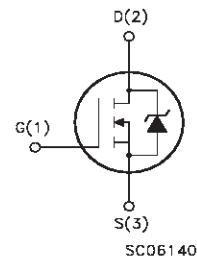
This Power Mosfet is the latest development of STMicroelectronics unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.



### APPLICATIONS

- DC-DC & DC-AC CONVERTERS
- MOTOR CONTROL, AUDIO AMPLIFIERS
- SOLENOID AND RELAY DRIVERS
- AUTOMOTIVE ENVIRONMENT

### INTERNAL SCHEMATIC DIAGRAM



### ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source Voltage (V <sub>GS</sub> = 0)	30	V
V <sub>DGR</sub>	Drain-gate Voltage (R <sub>GS</sub> = 20 kΩ)	30	V
V <sub>GS</sub>	Gate- source Voltage	+20	V
I <sub>D</sub>	Drain Current (continuos) at T <sub>C</sub> = 25°C	17	A
I <sub>D</sub>	Drain Current (continuos) at T <sub>C</sub> = 100°C	12	A
I <sub>DM</sub> (●)	Drain Current (pulsed)	68	A
P <sub>TOT</sub>	Total Dissipation at T <sub>C</sub> = 25°C	20	W
	Derating Factor	0.13	W/°C
dv/dt (1)	Peak Diode Recovery voltage slope	6	V/ns
E <sub>AS</sub> (2)	Single Pulse Avalanche Energy	200	mJ
T <sub>stg</sub>	Storage Temperature	-65 to 175	°C
T <sub>j</sub>	Max. Operating Junction Temperature	175	°C

(●) Pulse width limited by safe operating area

(1) I<sub>SD</sub> ≤ 17A, di/dt ≤ 300A/μs, V<sub>DD</sub> ≤ V<sub>(BR)DSS</sub>, T<sub>j</sub> ≤ T<sub>JMAX</sub>.

(2) Starting T<sub>j</sub>=25°C, I<sub>D</sub>=11A, V<sub>DD</sub>=15V

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### THERMAL DATA

Rthj-case	Thermal Resistance Junction-case Max	7.5	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	62.5	°C/W
T <sub>L</sub>	Maximum Lead Temperature For Soldering Purpose	275	°C

### ELECTRICAL CHARACTERISTICS (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0	30			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	V <sub>DS</sub> = Max Rating V <sub>DS</sub> = Max Rating, T <sub>C</sub> = 125 °C			1 10	μA μA
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ±20V			±100	nA

### ON (1)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1			V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 8.5 A V <sub>GS</sub> = 5 V, I <sub>D</sub> = 8.5 A		0.038 0.045	0.05 0.06	Ω
I <sub>D(on)</sub>	On State Drain Current	V <sub>DS</sub> > I <sub>D(on)</sub> x R <sub>DS(on)max</sub> , V <sub>GS</sub> = 10V	17			A

### DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g <sub>fs</sub> (1)	Forward Transconductance	V <sub>DS</sub> > I <sub>D(on)</sub> x R <sub>DS(on)max</sub> , I <sub>D</sub> = 11A		7		S
C <sub>iss</sub>	Input Capacitance			330		pF
C <sub>oss</sub>	Output Capacitance			90		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	V <sub>DS</sub> = 25V, f = 1 MHz, V <sub>GS</sub> = 0		40		pF

**ELECTRICAL CHARACTERISTICS (CONTINUED)****SWITCHING ON**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 15V, I_D = 8.5A$ $R_G = 4.7\Omega, V_{GS} = 4.5V$ (see test circuit, Figure 3)		11		ns
$t_r$	Rise Time			100		ns
$Q_g$	Total Gate Charge	$V_{DD} = 24V, I_D = 17A$ , $V_{GS} = 10V$		6.5	9	nC
$Q_{gs}$	Gate-Source Charge			3.6		nC
$Q_{gd}$	Gate-Drain Charge			2		nC

**SWITCHING OFF**

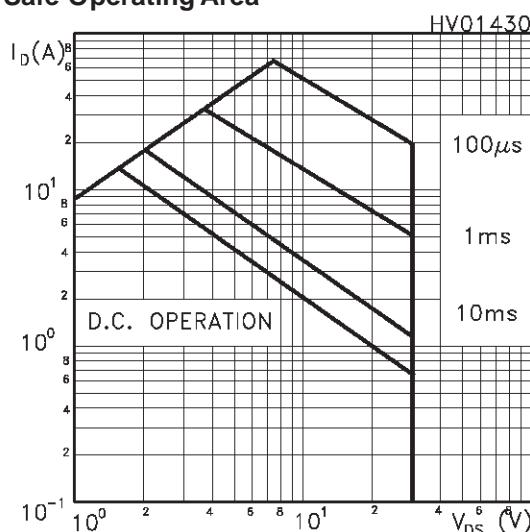
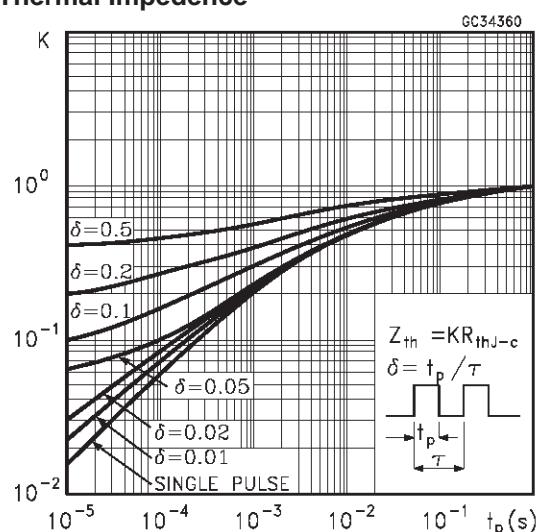
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$	Turn-off-Delay Time	$V_{DD} = 15V, I_D = 8.5A$ , $R_G = 4.7\Omega, V_{GS} = 4.5V$ (see test circuit, Figure 3)		25		ns
$t_f$	Fall Time			22		ns
$t_{r(off)}$	Off-voltage Rise Time	$V_{clamp} = 24V, I_D = 17A$ $R_G = 4.7\Omega, V_{GS} = 4.5V$		22		ns
$t_f$	Fall Time	(see test circuit, Figure 5)		55		ns
$t_c$	Cross-over Time			75		ns

**SOURCE DRAIN DIODE**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain Current				17	A
$I_{SDM}(1)$	Source-drain Current (pulsed)				68	A
$V_{SD}(2)$	Forward On Voltage	$I_{SD} = 17A, V_{GS} = 0$			1.5	V
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 17A, dI/dt = 100A/\mu s$ , $V_{DD} = 15V, T_j = 150^\circ C$ (see test circuit, Figure 5)		30		ns
$Q_{rr}$	Reverse Recovery Charge			18		nC
$I_{RRM}$	Reverse Recovery Current			1.2		A

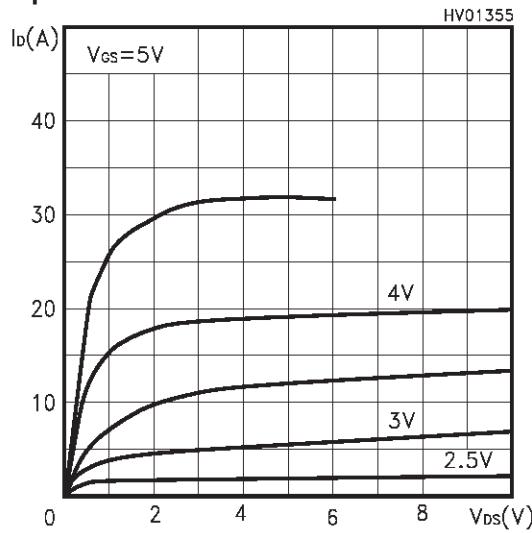
Note: 1. Pulsed: Pulse duration = 300  $\mu s$ , duty cycle 1.5 %.

2. Pulse width limited by safe operating area.

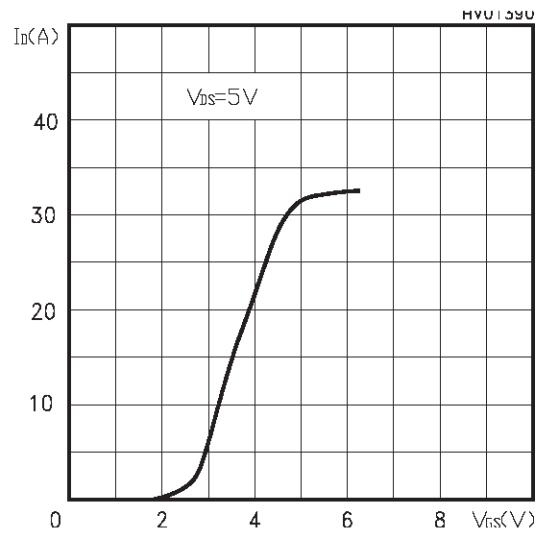
**Safe Operating Area****Thermal Impedance**

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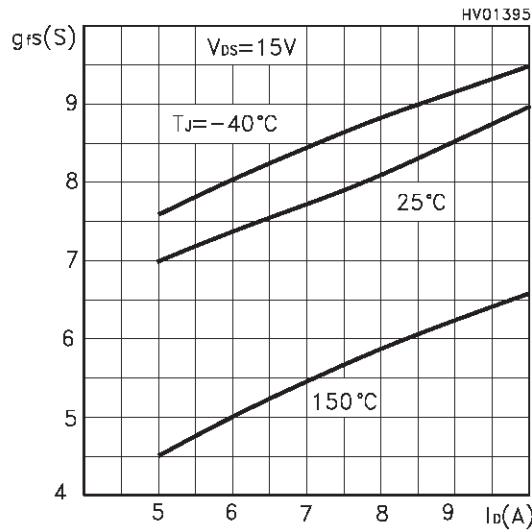
### Output Characteristics



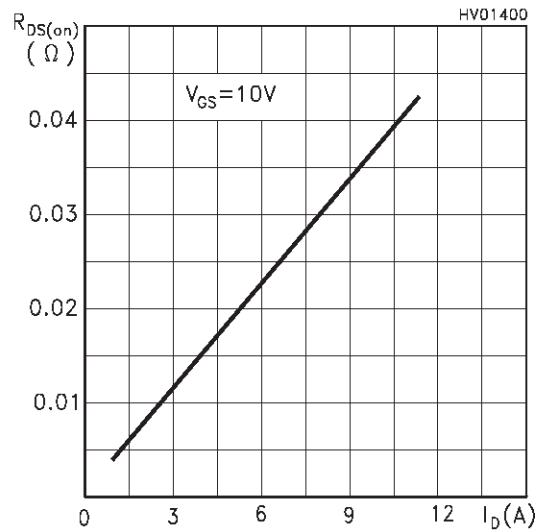
### Transfer Characteristics



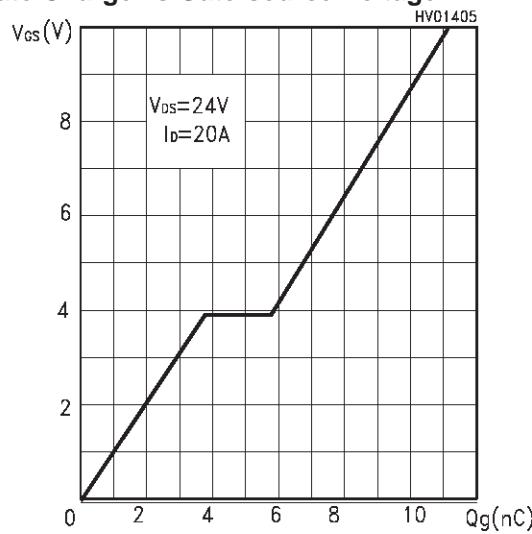
### Transconductance



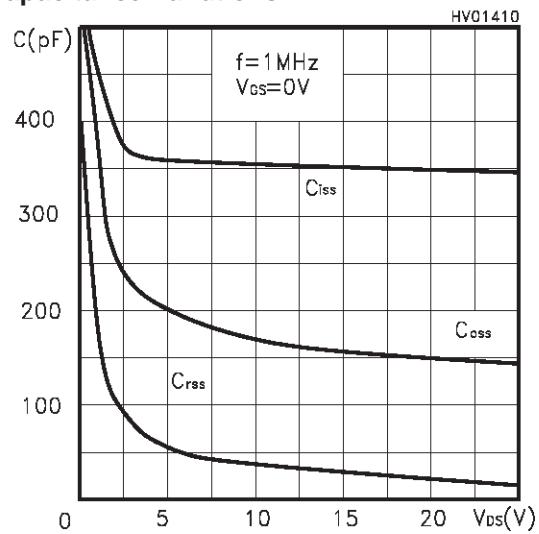
### Static Drain-source On Resistance

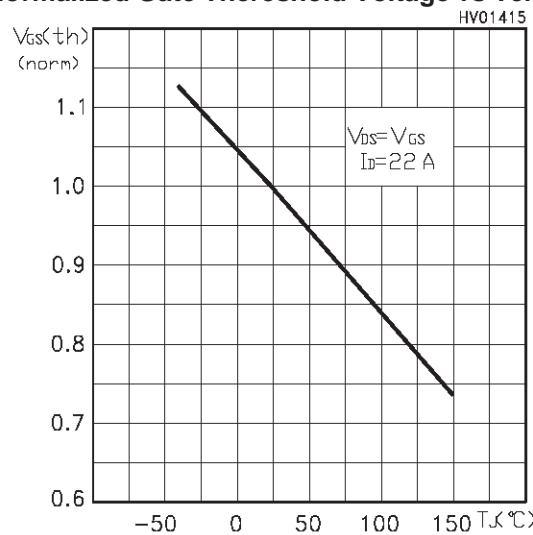
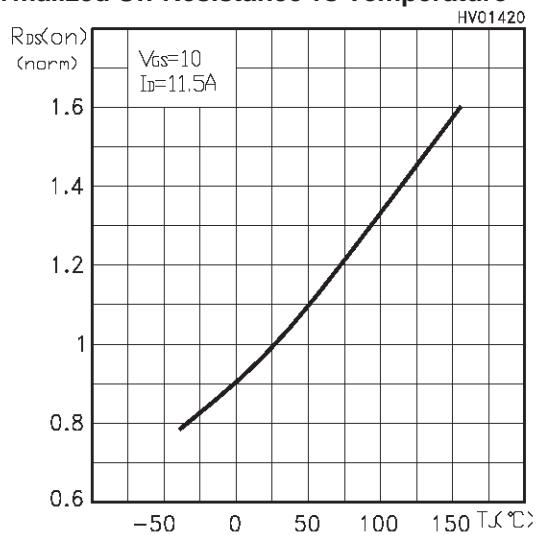
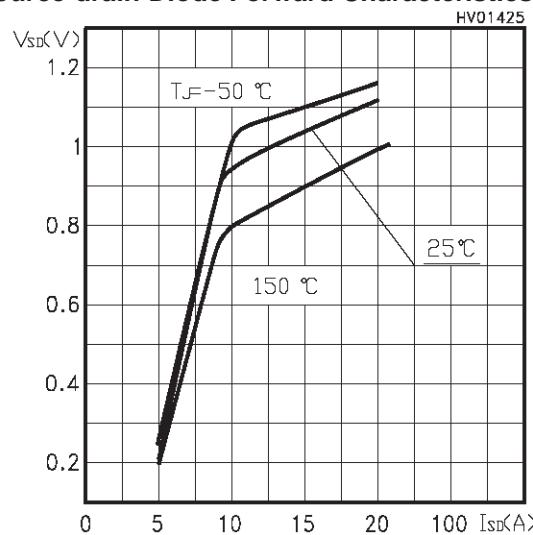


### Gate Charge vs Gate-source Voltage



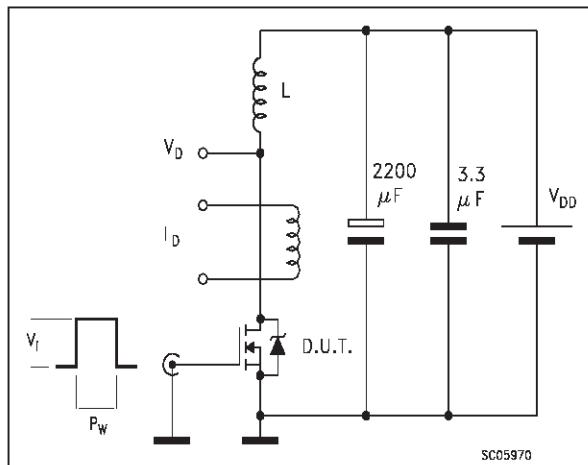
### Capacitance Variations



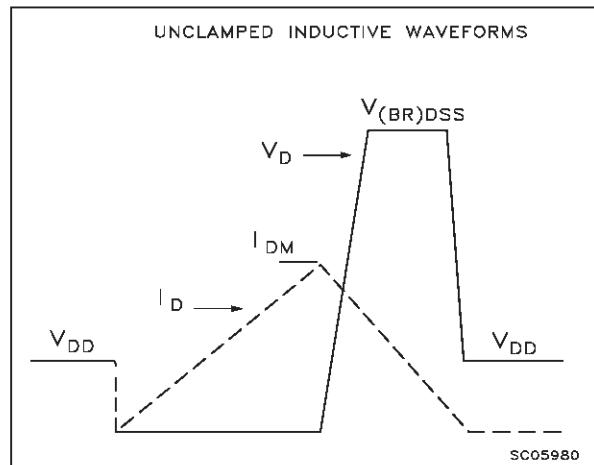
**Normalized Gate Threshold Voltage vs Temp.****Normalized On Resistance vs Temperature****Source-drain Diode Forward Characteristics**

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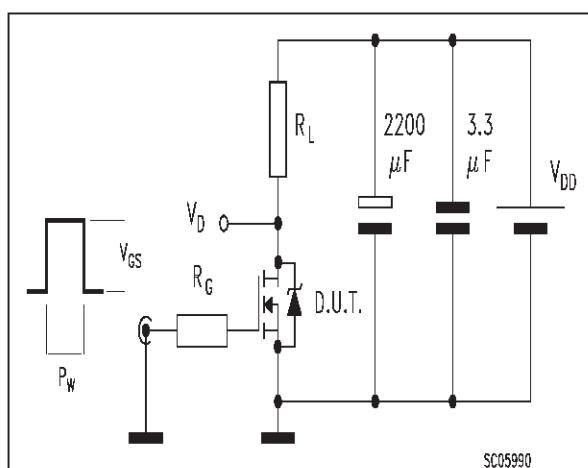
**Fig. 1:** Unclamped Inductive Load Test Circuit



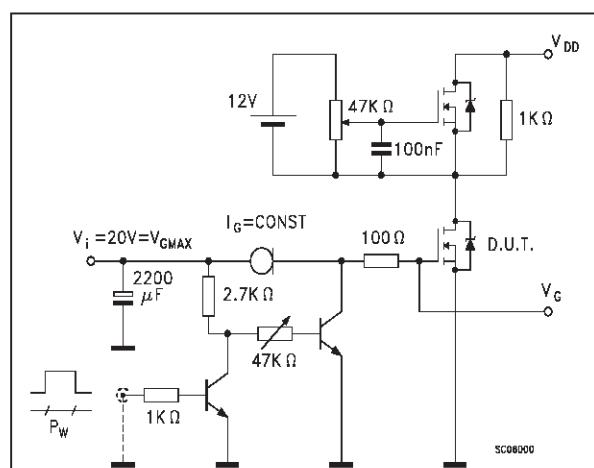
**Fig. 2:** Unclamped Inductive Waveform



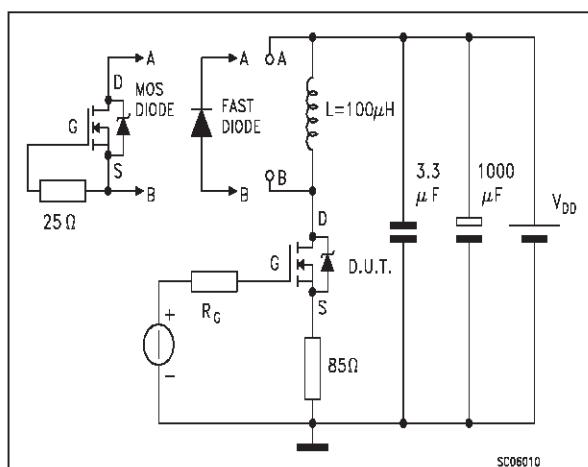
**Fig. 3:** Switching Times Test Circuit For Resistive Load



**Fig. 4:** Gate Charge test Circuit

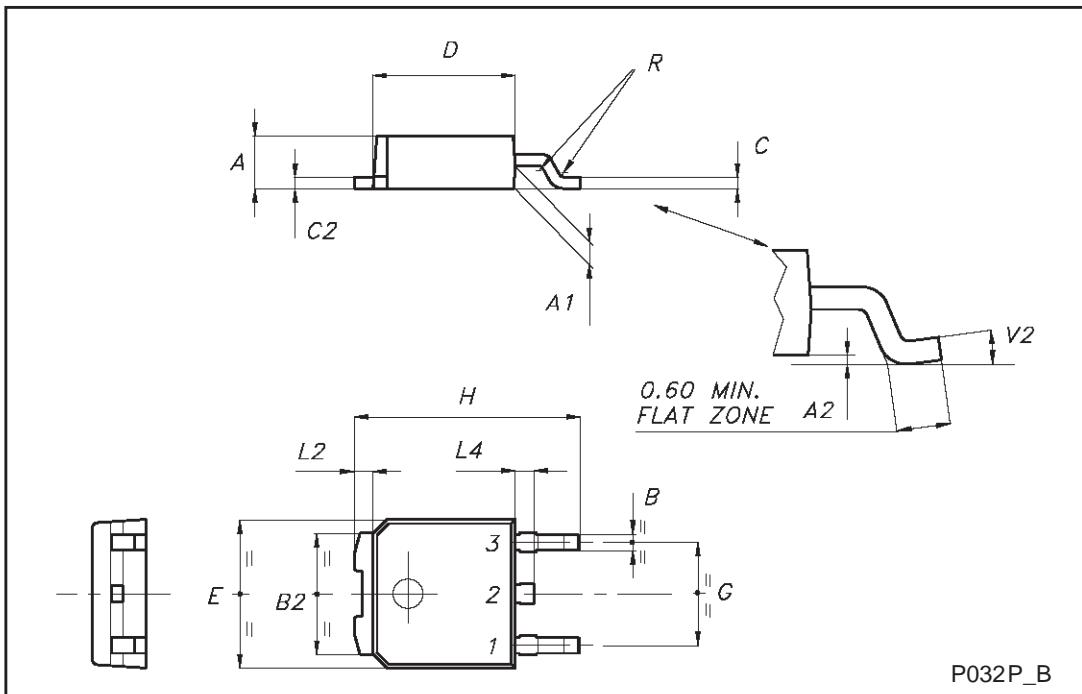


**Fig. 5:** Test Circuit For Inductive Load Switching And Diode Recovery Times



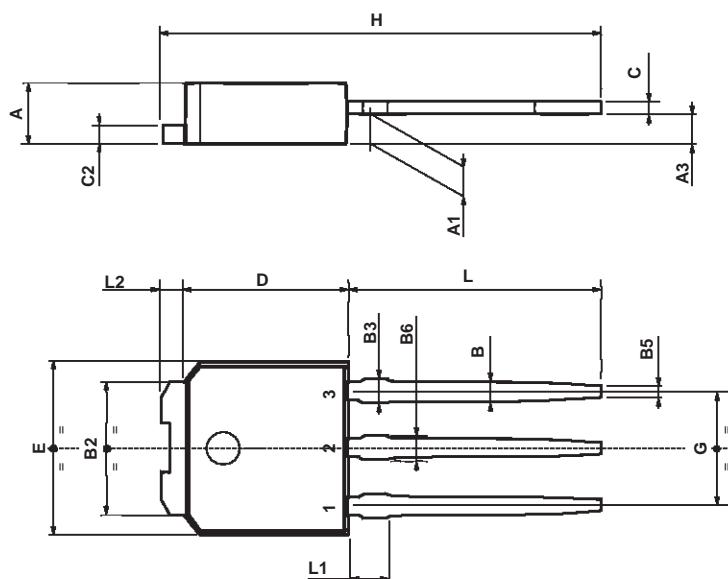
## TO-252 (DPAK) MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	2.20		2.40	0.087		0.094
A1	0.90		1.10	0.035		0.043
A2	0.03		0.23	0.001		0.009
B	0.64		0.90	0.025		0.035
B2	5.20		5.40	0.204		0.213
C	0.45		0.60	0.018		0.024
C2	0.48		0.60	0.019		0.024
D	6.00		6.20	0.236		0.244
E	6.40		6.60	0.252		0.260
G	4.40		4.60	0.173		0.181
H	9.35		10.10	0.368		0.398
L2		0.8			0.031	
L4	0.60		1.00	0.024		0.039
V2	0°		8°	0°		0°



## TO-251 (IPAK) MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
B	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
B3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
C	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
H	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



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